

An iterative approach to test time minimization for parallel hybrid BIST architectures

Ubar, Raimund-Johannes; Jenihhin, Maksim; Jervan, Gert; Peng, Z. System-on-Chip Conference 2004 : Bastad, Sweden 2004 / p. ? <https://www.ida.liu.se/labs/eslab/publications/pap/db/latw04.pdf>